

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8	((generat\$ same program\$) near connect\$) and (program\$ same run\$ same together)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:27
L2	47	plural\$ near (program\$ same run\$) and (program same generat\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:42
L3	0	717/106.ccls. and (program\$ same generat\$ same method) and (plural\$ same program\$) and (navigation\$ same program\$ same display\$) and (generat\$ same connect\$ same program\$) and input\$ and (user same authoriz\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:43
L4	31	(program\$ same generat\$ same method) and (plural\$ same program\$) and (navigation\$ same program\$ same display\$) and (generat\$ same connect\$ same program\$) and input\$ and (user same authoriz\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:25
L5	2	"20020087946".PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:52
S11	40	plural\$ near (program\$ same run\$) and (program same generat\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:41
S23	27	(program\$ same generat\$ same method) and (plural\$ same program\$) and (navigation\$ same program\$ same display\$) and (generat\$ same connect\$ same program\$) and input\$ and (user same authoriz\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 13:24
S24	0	717/106.ccls. and (program\$ same generat\$ same method) and (plural\$ same program\$) and (navigation\$ same program\$ same display\$) and (generat\$ same connect\$ same program\$) and input\$ and (user same authoriz\$)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/08/03 12:43



Key: IEEE JNL = IEEE Journal or Magazine, IEE JNL = IEE Journal or Magazine, IEEE CNF = IEEE Conference, IEE CNF = IEE Conference, IEEE STD = IEEE Standard

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